




Page i

RESISTORS, HEATERS, FLEXIBLE
ESCC Generic Specification No. 4009

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	ESCC Generic Specification		PAGE ii ISSUE 1
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Pages 1 to 37

RESISTORS, HEATERS, FLEXIBLE

ESA/SCC Generic Specification No. 4009



space components
coordination group

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TABLE OF CONTENTS

	<u>Page</u>
1. <u>INTRODUCTION</u>	6
1.1 Scope	6
1.2 Applicability	6
2. <u>APPLICABLE DOCUMENTS</u>	6
2.1 ESA/SCC Specifications	6
2.2 Other (Reference) Documents	7
2.3 Order of Precedence	7
3. <u>TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS</u>	7
4. <u>REQUIREMENTS</u>	7
4.1 General	7
4.1.1 Specifications	7
4.1.2 Conditions and Methods of Test	7
4.1.3 Manufacturer's Responsibility for Performance of Tests and Inspections	7
4.1.4 Inspection Rights	8
4.1.5 Pre-encapsulation Inspection	8
4.1.6 Wires for Terminal Leads	8
4.2 Qualification Approval Requirements on a Manufacturer	8
4.3 Deliverable Components	8
4.3.1 Lot Failure	8
4.3.2 Testing and Lot Acceptance Levels	9
4.4 Marking	9
4.5 Materials and Finishes	9
5. <u>PRODUCTION CONTROL</u>	9
5.1 General	9
5.2 Special In-process Controls	9
5.2.1 Solderability	9
5.2.2 Robustness of Terminations	9
6. <u>FINAL PRODUCTION TESTS</u>	11
6.1 General	11
6.2 Test Methods and Conditions	11
6.3 Documentation	11
7. <u>BURN-IN AND ELECTRICAL MEASUREMENTS</u>	11
7.1 General	11
7.1.1 Conditions of Test	11
7.1.2 Data Points	11
7.2 Failure Criteria	12
7.2.1 Parameter Drift Failure	12
7.2.2 Parameter Limit Failure	12
7.2.3 Other Failures	12
7.3 Failed Components	12
7.4 Lot Failure	12
7.4.1 Lot Failure during 100% Testing	12
7.4.2 Lot Failure during Sample Testing	12
7.5 Documentation	13



	<u>Page</u>
8. <u>QUALIFICATION APPROVAL AND LOT ACCEPTANCE TESTS</u>	13
8.1 Qualification Testing	13
8.1.1 General	13
8.1.2 Distribution within the Qualification Test Lot	13
8.2 Lot Acceptance Testing	13
8.2.1 General	13
8.2.2 Distribution within the Sample for Lot Acceptance Testing	14
8.2.3 Lot Acceptance Level 3 Testing	14
8.2.4 Lot Acceptance Level 2 Testing	14
8.2.5 Lot Acceptance Level 1 Testing	15
8.3 Failure Criteria	15
8.3.1 Environmental and Mechanical Test Failures	15
8.3.2 Electrical Failures	15
8.3.3 Other Failures	15
8.4 Failed Components	15
8.5 Lot Failure	16
8.6 Documentation	16
9. <u>TEST METHODS AND PROCEDURES</u>	21
9.1 Overload	21
9.1.1 Mounting	21
9.1.2 Procedure	21
9.2 Permanence of Marking	21
9.3 Radiographic Inspection	21
9.4 Dimension Check	21
9.5 Electrical Measurements	21
9.5.1 General	21
9.5.2 Parameter Drift Value Measurements	23
9.5.3 Electrical Measurements at High and Low Temperatures	23
9.5.4 Electrical Measurements at Room Temperature	23
9.5.5 Electrical Measurements during Endurance Testing	23
9.6 External Visual Inspection	23
9.7 Temperature Coefficient	23
9.7.1 Procedure I	23
9.7.2 Procedure II	23
9.7.3 Test Procedure	23
9.8 High Temperature Storage	24
9.9 Solderability	25
9.9.1 Procedure	25
9.9.2 Final Examination	25
9.10 Robustness of Terminations	25
9.10.1 Initial Measurement	25
9.10.2 Procedure	25
9.10.3 Final Measurement	25
9.11 Burn-in	25
9.12 Rapid Change of Temperature	25
9.12.1 Initial Measurement	25
9.12.2 Procedure and Recovery	25
9.12.3 Final Measurement	26
9.13 Low Temperature Operation	26
9.13.1 Initial Measurement	26
9.13.2 Procedure and Recovery	26
9.13.3 Final Measurement	26



	<u>Page</u>
9.14 Climatic Sequence	27
9.14.1 Initial Measurement	27
9.14.2 Dry Heat	27
9.14.3 Damp Heat (Accelerated) First Cycle	27
9.14.4 Cold Test	27
9.14.5 Low Air Pressure	27
9.14.6 Damp Heat (Accelerated) Remaining Cycles	28
9.14.7 D.C. Load	28
9.14.8 Final Measurement	28
9.15 Operating Life	28
9.15.1 Operating Life during Qualification Testing	28
9.15.2 Operating Life during Lot Acceptance Testing	29
10. <u>DATA DOCUMENTATION</u>	31
10.1 General	31
10.1.1 Qualification Approval	31
10.1.2 Testing Level 'B'	31
10.1.3 Testing Level 'C'	31A
10.1.4 Data Retention/Data Access	31A
10.2 Cover Sheet(s)	32
10.3 List of Equipment Used	32
10.4 List of Test References	32
10.5 Special In-process Control Data	32
10.6 Final Production Test Data	32
10.7 Burn-in and Electrical Measurement Data	33
10.7.1 Testing Level 'B'	33
10.7.2 Testing Level 'C'	33
10.8 Qualification Test Data	33
10.9 Lot Acceptance Test Data	33
10.9.1 Testing Level 'B'	33
10.9.2 Testing Level 'C'	33
10.10 Failed Components List and Failure Analysis Report	34
10.11 Certificate of Conformity	34
11. <u>DELIVERY</u>	34
12. <u>PACKAGING AND DESPATCH</u>	34
<u>CHARTS</u>	
I TESTING LEVELS	10
II FINAL PRODUCTION TESTS	17
III BURN-IN AND ELECTRICAL MEASUREMENTS	18
IV QUALIFICATION TESTS	19
V LOT ACCEPTANCE TESTS	20
<u>ANNEXES</u>	
I LTPD SAMPLING PLAN FOR LOT SIZES GREATER THAN 200 DEVICES	35
LTPD SAMPLING PLAN FOR LOT SIZES LESS THAN OR EQUAL TO 200 DEVICES	36

**1. INTRODUCTION****1.1 SCOPE**

This specification defines the general requirements for the qualification approval, procurement, including lot acceptance testing, and delivery of Resistors, Heaters, Flexible for space applications.

This specification contains the appropriate inspection and test schedules and also specifies the data documentation requirements.

1.2 APPLICABILITY

This specification is primarily applicable to the granting of qualification approval to a component in accordance with ESA/SCC Basic Specification No. 20100 and the procurement of such components from qualified Manufacturers.

2. APPLICABLE DOCUMENTS

The following documents form part of, and shall be read in conjunction with, this specification. The relevant issues shall be those in effect on the date of placing the purchase order.

2.1 ESA/SCC SPECIFICATIONS

No. 20100, Requirements for the Qualification of Standard Electronic Components for Space Application.

No. 20500, External Visual Inspection.

No. 20600, Preservation, Packaging and Despatch of SCC Electronic Components.

No. 20900, Radiographic Inspection

No. 21300, Terms, Definitions, Abbreviations, Symbols and Units.

No. 21700, General Requirements for the Marking of SCC Components.

No. 22800, ESA/SCC Non-conformance Control System.

No. 23500, Lead Materials and Finishes for Components for Space Application.

No. 24600, Minimum Quality System Requirements.

No. 24800, Resistance to Solvents of Marking, Materials and Finishes.

With the exception of ESA/SCC Basic Specifications Nos. 20100, 21700, 22800 and 24600, where Manufacturers' specifications are equivalent to, or more stringent than, the ESA/SCC Basic Specifications listed above, they may be used in place of the latter, subject to the approval of the appropriate Qualifying Space Agency.

Such replacements shall be clearly identified in the applicable Process Identification Document (P.I.D.) and listed in an appendix to the appropriate Detail Specification.

Unless otherwise stated herein, references within the text of this specification to "the Detail Specification" shall mean the relevant ESA/SCC Detail Specification.



2.2 OTHER (REFERENCE) DOCUMENTS

IEC Publication No. 68, Basic Environmental Testing Procedures.

IEC Publication No. 115, Fixed Resistors for Use in Electronic Equipment.

IEC Publication No. 410, Sampling Plans and Procedures for Inspection by Attributes.

ESA PSS-01-702, A Thermal Vacuum Test for the Screening of Space Materials.

2.3 ORDER OF PRECEDENCE

For the purpose of interpretation and in case of conflict with regard to documentation, the following order of precedence shall apply:-

- (a) ESA/SCC Detail Specification.
- (b) ESA/SCC Generic Specification.
- (c) ESA/SCC Basic Specification.
- (d) Other documents, if referenced herein.

3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS

The terms, definitions, abbreviations, symbols and units specified in ESA/SCC Basic Specification No. 21300 shall apply.

4. REQUIREMENTS

4.1 GENERAL

The test requirements for qualification approval of a component shall comprise final production tests (see Chart II), burn-in and electrical measurements to testing level 'B' (see Chart III) and qualification testing (see Chart IV).

The test requirements for procurement of components shall comprise final production tests (Chart II), burn-in and electrical measurements to testing level 'B' or 'C' as required (Chart III) together with, when applicable, a level of lot acceptance testing (see Chart V) to be specified by the Orderer.

If a Manufacturer elects to eliminate a final production test by substituting an in-process control or statistical process control procedure, the Manufacturer is still responsible for delivering components that meet all of the performance, quality and reliability requirements defined in this specification and the Detail Specification.

4.1.1 Specifications



For qualification approval, procurement (including lot acceptance testing) and delivery of components in conformity with this specification, the specifications listed in Section 2 of this document shall apply in total unless otherwise specified herein or in the Detail Specification.

4.1.2 Conditions and Methods of Test

The conditions and methods of test shall be in accordance with this specification, the ESA/SCC Basic Specifications referenced herein and the Detail Specification.

4.1.3 Manufacturer's Responsibility for Performance of Tests and Inspections

The Manufacturer shall be responsible for the performance of tests and inspections required by the applicable specifications. These tests and inspections shall be performed at the plant of the Manufacturer of the components unless it is agreed by the Qualifying Space Agency prior to commencing qualification testing, or procurement, to use an approved external facility.

		<p style="text-align: center;">ESA/SCC Generic Specification No. 4009</p>	<p style="text-align: center;">Rev. 'A'</p>	<p>PAGE 8 ISSUE 3</p>
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4.1.4 Inspection Rights

The Qualifying Space Agency (for qualification approval or for a procurement) reserves the right to monitor any of the tests and inspections scheduled in the applicable specifications.

4.1.5 Pre-encapsulation Inspection

Not applicable.

4.1.6 Wires for Terminations

Wires used for terminal leads shall be ESA/SCC qualified.

4.2 QUALIFICATION APPROVAL REQUIREMENTS ON A MANUFACTURER

To obtain and maintain the qualification approval of a component, or family of components, a Manufacturer shall satisfy the requirements of ESA/SCC Basic Specification No. 20100.

4.3 DELIVERABLE COMPONENTS

Components delivered to this specification shall be processed and inspected in accordance with the relevant Process Identification Document (P.I.D.). Each delivered component shall be traceable to its production lot. Components delivered to this specification shall have completed satisfactorily all tests to the testing level and lot acceptance level specified in the purchase order (see Para. 4.3.2).

ESA/SCC qualified components delivered to this specification shall be produced from lots that are capable of passing all tests, and sequences of tests, that are defined in Charts IV and V. The Manufacturer shall not knowingly supply components that cannot meet this requirement. In the event that, subsequent to delivery and prior to operational use, a component is found to be in a condition such that it could not have passed these tests at the time of manufacture, this shall be grounds for rejection of the delivered lot.

Components failing inspections and tests of the higher testing level (i.e. level 'B') shall not be supplied against any order for components of the lower testing level.

4.3.1 Lot Failure

Lot failure may occur during final production tests (Chart II), burn-in and electrical measurements (Chart III), qualification testing (Chart IV) or lot acceptance testing (Chart V).



Should such failure occur, the non-conformance procedure shall be initiated in accordance with ESA/SCC Basic Specification No. 22800.

Should such failure occur during procurement, the Manufacturer shall notify the Orderer by telex within 2 working days, giving details of the number and mode of failure and the suspected cause.

In the case where qualification approval has been granted to the component, he shall, at the same time by the same means, inform the Qualifying Space Agency in order that the latter may consider its implications.

No further testing shall be performed on the failed components except on instruction from the Orderer. The Orderer shall inform the Manufacturer and the Qualifying Space Agency within 2 working days of receipt of the telex, by the same means, what action shall be taken.

In the case when lot failure occurs during qualification testing, the Manufacturer shall immediately notify the appropriate Qualifying Space Agency who will define a course of action to be followed. No further testing shall be performed on the failed components.

		<p style="text-align: center;">ESA/SCC Generic Specification No. 4009</p>	<p>PAGE 9 ISSUE 3</p>
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4.3.2 Testing and Lot Acceptance Levels

This specification defines 2 levels of testing severity which are designated by the letters 'B' and 'C' (see Chart I) and 3 levels of lot acceptance testing (see Chart V).

The lot acceptance levels are designated 1, 2 and 3 and are comprised of tests as follows:-

Level 3 (LA3) - Electrical Subgroup.

Level 2 (LA2) - Endurance Subgroup
plus Electrical Subgroup.

Level 1 (LA1) - Environmental and Mechanical Subgroup
plus Endurance Subgroup
plus Electrical Subgroup.

The required testing level and lot acceptance level shall both be specified in a purchase order.

4.4 MARKING

All components procured and delivered to this specification from a source qualified according to ESA/SCC Basic Specification No. 20100 shall be marked in accordance with ESA/SCC Basic Specification No. 21700. Thus, they shall bear the ESA symbol to signify their conformance to the ESA/SCC qualification approval requirements and full compliance with the requirements of this specification and the Detail Specification.

Components procured from sources which are not ESA/SCC qualified, provided that they fully comply with the procurement requirements of this specification and the Detail Specification, may bear the SCC marking **with the exception of the ESA symbol.**

4.5 MATERIALS AND FINISHES

All non-metallic materials and finishes, that are not within a hermetically sealed enclosure, of the components specified herein shall meet the outgassing requirements as outlined in ESA PSS-01-702. Specific requirements for materials and finishes are specified in the Detail Specification.

5. PRODUCTION CONTROL

5.1 GENERAL

The minimum requirements for production control, which are equally applicable to procurement, are defined in ESA/SCC Basic Specification No. 20100, Para's 5.1 and 5.2.

5.2 SPECIAL IN-PROCESS CONTROLS

Where applicable, additional special in-process controls to those described below shall be specified in the Detail Specification.

5.2.1 Solderability

For each lot, before assembly of wires onto heaters, a solderability test as per Para. 9.9 of this specification may be performed.

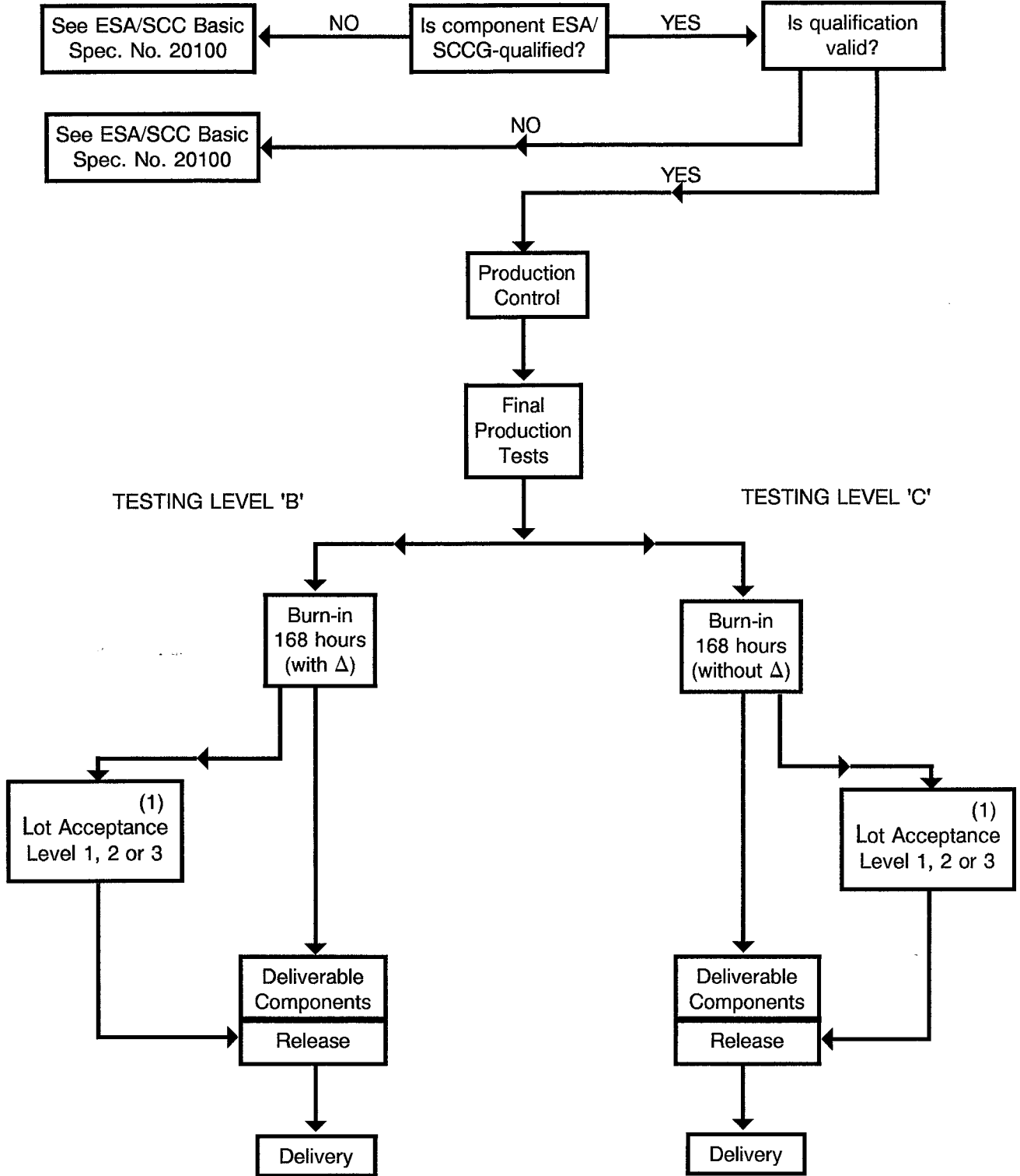
Two samples of the wires with a length of 150mm shall be stripped of insulation over a length of 50mm from both ends.

5.2.2 Robustness of Terminations

All flexible heaters may be subjected to Test 'Ua1' of IEC Publication No. 68-2-21. The strength and duration of the pull forces are given in the Detail Specification.



CHART I - TESTING LEVELS



NOTES

1. When applicable.

**6. FINAL PRODUCTION TESTS****6.1 GENERAL**

Unless otherwise specified in the Detail Specification, all components used for qualification testing and all components for delivery, including those submitted to lot acceptance tests, shall be subjected to tests and inspections in accordance with Chart II.

Unless otherwise specified in the Detail Specification, the tests shall be performed in the order shown.

Any components that do not meet these requirements shall be removed from the lot and at no future time be re-submitted to the requirements of this specification.

6.2 TEST METHODS AND CONDITIONS

The applicable test methods and conditions are specified in the paragraphs referenced in Chart II of this specification.

6.3 DOCUMENTATION

Documentation of final production test data shall be in accordance with the requirements of Para. 10.6 of this specification.

7. BURN-IN AND ELECTRICAL MEASUREMENTS**7.1 GENERAL**

Unless otherwise specified in the Detail Specification, all components used for qualification testing and all components for delivery, including those submitted to lot acceptance tests, shall be subjected to tests and inspections in accordance with Chart III.

Unless otherwise specified in the Detail Specification, the tests shall be performed in the order shown.

The applicable test methods and conditions are specified in the paragraphs referenced in Chart III.

Components of testing level 'B' shall be serialised prior to the tests and inspections.

7.1.1 Conditions of Test

The conditions for burn-in shall be as shown in Table 5 of the Detail Specification.

Unless otherwise specified in the Detail Specification, components of both levels 'B' and 'C' shall be subjected to a total burn-in period of 168 hours.

7.1.2 Data Points

For components of testing level 'B', undergoing a total burn-in period of 168 hours, the data points for parameter drift measurements shall be 0 hours (initial) and 168(+24-0) hours (final).

For components of testing level 'C', undergoing a total burn-in of 168 hours, the data point for post-burn-in electrical measurements shall be 168(+24-0) hours.



7.2 FAILURE CRITERIA

7.2.1 Parameter Drift Failure

The acceptable delta limits are shown in Table 4 of the Detail Specification. A component of testing level 'B' shall be counted as a parameter drift failure if the changes during burn-in are larger than the delta (Δ) values specified.

7.2.2 Parameter Limit Failure

A component shall be counted as a limit failure if one or more parameters exceed the limits shown in Tables 2 or 3 of the Detail Specification.

Any component which exhibits a limit failure prior to the burn-in sequence shall be rejected and not counted when determining lot rejection.

7.2.3 Other Failures

A component shall be counted as a failure in any of the following cases:

- Mechanical failure.
- Handling failure.
- Lost component.

7.3 FAILED COMPONENTS

A component shall be considered as a failed component if it exhibits one or more of the failure modes described in Para. 7.2 of this specification.

7.4 LOT FAILURE

In the case of lot failure, the Manufacturer shall act in accordance with the requirements of Para. 4.3.1 of this specification.

7.4.1 Lot Failure during 100% Testing

If the number of components failed on the basis of the failure criteria described in Para. 7.2 exceeds 5% (rounded upwards to the nearest whole number) of the number of components submitted to burn-in and electrical measurements, the lot shall be considered as failed.



If a lot is composed of groups of components of one family defined in one ESA/SCC Detail Specification, but separately identifiable for any reason, then the lot failure criteria shall apply separately to each identifiable group.

7.4.2 Lot Failure during Sample Testing

A lot shall be considered as failed if the number of allowable failures during sample testing in accordance with General Inspection Level II of IEC Publication No. 410 and the applicable AQL as specified in the Detail Specification, is exceeded.

In the case where an LTPD is specified in the Detail Specification, a lot shall be considered as failed if the number of failures allowed is exceeded (see Annexe I for LTPD Sampling Plan).

If a lot failure occurs in either case, a 100% testing may be performed with the lot failure criteria given in Para. 7.4.1.

		<p>ESA/SCC Generic Specification No. 4009</p>	<p>Rev. 'B'</p>	<p>PAGE 13</p>	<p>ISSUE 3</p>
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7.5 DOCUMENTATION

Data documentation of burn-in and electrical measurements shall be in accordance with Para. 10.7 of this specification.

8. QUALIFICATION APPROVAL AND LOT ACCEPTANCE TESTS

8.1 QUALIFICATION TESTING

8.1.1 General

Qualification testing shall be in accordance with the requirements of Chart IV of this specification. The tests of Chart IV shall be performed on the specified sample, chosen at random from components which have successfully passed the tests in Charts II and III for testing level 'B'. This sample constitutes the qualification test lot.

The qualification test lot is divided into subgroups of tests and all components assigned to a subgroup shall be subjected to all of the tests in that subgroup, in the sequence shown.

The applicable test requirements are detailed in the paragraphs referenced in Chart IV.

The conditions governing qualification testing are given in ESA/SCC Basic Specification No. 20100, Para. 5.3 and, for the extension or renewal of qualification approval, in Paras. 6.3 and 6.4.

8.1.2 Distribution within the Qualification Test Lot

A minimum sample of 60 components shall be submitted to qualification testing (Chart IV). The distribution within the sample shall be as follows:

- $\frac{1}{3}$ of the lot with the maximum resistive density.
- $\frac{1}{3}$ of the lot with the average resistive density (10 to 30 Ohms/cm²).
- $\frac{1}{3}$ of the lot of the double layer type with separate outputs.

The selected distribution shall be agreed with the Qualifying Space Agency.

8.2 LOT ACCEPTANCE TESTING

8.2.1 General

The sample sizes of the 3 lot acceptance levels are specified in Chart V. All components assigned to a subgroup shall be subjected to all of the tests of that subgroup in the sequence shown.

The tests to Chart V shall be performed on the specified sample which shall have been chosen, whenever possible, at random from the proposed delivery lot (but see Para. 8.2.3(b)). The applicable test requirements are detailed in the paragraphs referenced in Chart V.

As a minimum for procurement of non-qualified components, lot acceptance level 3 tests shall apply. For procurement of qualified components, lot acceptance testing shall be performed if specified in a purchase order. Procurement lots ordered with a lot acceptance test level shall be delivered only after successful completion of lot acceptance testing.



8.2.2 Distribution within the Sample for Lot Acceptance Testing

Where a Detail Specification covers a range or series of components that are considered similar, then it may be necessary that the sample for lot acceptance testing be comprised of component types so selected that they adequately represent all of the various mechanical, structural and electrical peculiarities of the procured range or series.

The distribution of the component types will normally vary from procurement to procurement and shall be as specified by the Orderer, following as closely as possible the requirements prescribed in Para. 8.1.2 of this specification.

8.2.3 Lot Acceptance Level 3 Testing (LA3)

Lot acceptance level 3 tests are designated as the electrical subgroup and comprise electrical measurements of characteristics and tests to prove the assembly capability of the component. For LA3 testing, the following requirements and conditions shall apply:-

- (a) LA3 testing shall be performed by the Manufacturer's quality assurance personnel using dedicated quality assurance equipment whenever possible. LA3 testing shall not be a repetition of routine measurements made by production personnel during final production tests and burn-in and electrical measurements.
- (b) When tests to Tables 2 and 3 of the Detail Specification have been performed on a sample basis, then the components for LA3 testing shall be selected from this sample.
- (c) The electrical measurements for LA3 are considered to be non-destructive and therefore components so tested may form part of the delivery lot.
- (d) The solderability and robustness of termination tests are considered to be destructive and therefore components so tested shall not form part of the delivery lot. Post-burn-in electrical rejects may be used for these tests.
- (e) When required in the purchase order, the Manufacturer shall notify the Orderer at least 2 working weeks before commencement of LA3 testing. The Orderer shall indicate immediately whether or not he intends to witness the tests.

8.2.4 Lot Acceptance Level 2 Testing (LA2)

Lot acceptance level 2 testing shall comprise the tests for LA3 (electrical subgroup) plus tests on an endurance subgroup. For the electrical subgroup, the requirements and conditions as for LA3 (see Para. 8.2.3) shall apply.

For the endurance subgroup, the following shall apply:-

- (a) Components of testing level 'C', selected for the endurance subgroup, shall be serialised prior to the tests.
- (a) The tests in this subgroup are considered to be destructive and therefore components (of testing level 'B' or 'C') so tested shall not form part of the delivery lot.



8.2.5 Lot Acceptance Level 1 Testing (LA1)

Lot acceptance level 1 testing shall comprise the tests for LA3 (electrical subgroup) and LA2 (endurance subgroup) plus tests on an environmental and mechanical subgroup. For the electrical and endurance subgroups, the requirements and conditions for LA3 (see Para. 8.2.3) and LA2 (see Para. 8.2.4) respectively shall apply.

For the environmental subgroup, the following shall apply:-

- (a) Components of testing level 'C', selected for the environmental subgroup, shall be serialised prior to the tests.
- (b) The tests in this subgroup are considered to be destructive and therefore components (of testing level 'B' or 'C') so tested shall not form part of the delivery lot.

8.3 FAILURE CRITERIA

The following criteria shall apply to qualification testing and to lot acceptance testing.

8.3.1 Environmental and Mechanical Test Failures

The following shall be counted as component failures:

- Components which fail tests for which the pass/fail criteria are inherent in the test method, e.g. solderability, robustness of terminations, etc.

8.3.2 Electrical Failures

The following shall be counted as component failures:-

- (a) Components which, when subjected to electrical measurements on completion of environmental tests, in accordance with either Table 2 or Table 6, as specified in the Detail Specification, fail one or more the applicable limits.
- (b) Components which, when subjected to electrical measurements at intermediate and end-points during endurance testing, in accordance with Table 6 of the Detail Specification, fail one or more of the applicable limits.
- (c) Components which, when subjected to measurement of electrical characteristics, in accordance with Tables 2 and 3 of the Detail Specification, fail one or more of the applicable limits.

8.3.3 Other Failures

The following additional failures may also occur during qualification testing or lot acceptance testing:-

- (a) Components failing to comply with the requirements of ESA/SCC Basic Specification No. 20500.
- (b) Lost components.

8.4 FAILED COMPONENTS

A component shall be considered as failed if it exhibits one or more of the failure modes detailed in Para. 8.3 of this specification. The allowable number of failed components per Subgroup, the aggregate failure constraints and the permitted distribution of such failures are shown at the foot of Charts IV and V of this specification.

When requested by the Qualifying Space Agency or the Orderer, failure analysis of failed components shall be performed by the Manufacturer and the results provided.

Failed components from successful lots shall be marked as such and be stored at the Manufacturer's plant for 24 months.



8.5 LOT FAILURE

A lot shall be considered as failed if the allowable number of failures according to Chart IV or V of this specification, as relevant, has been exceeded.

In the case of lot failure, the Manufacturer shall act in accordance with Para. 4.3.1 of this specification.

8.6 DOCUMENTATION

For qualification testing, the qualification test data shall be documented in accordance with the requirements of Para. 10.8 of this specification.

In the case of lot acceptance testing, the data shall be documented in accordance with the requirements of Para. 10.9 of this specification.



CHART II- FINAL PRODUCTION TESTS

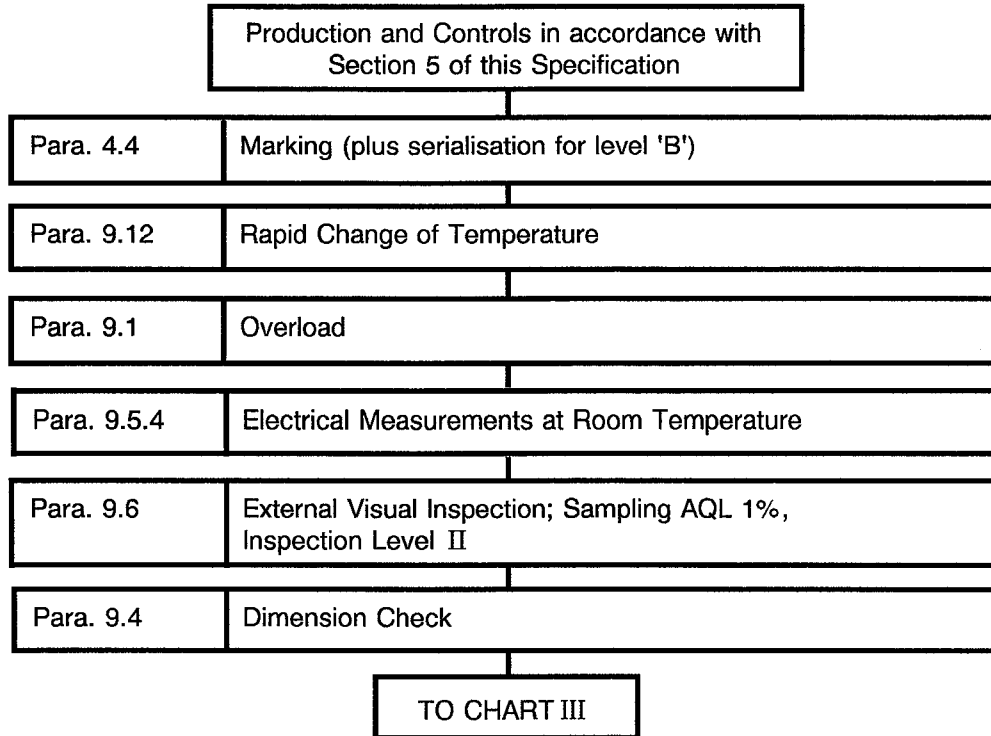
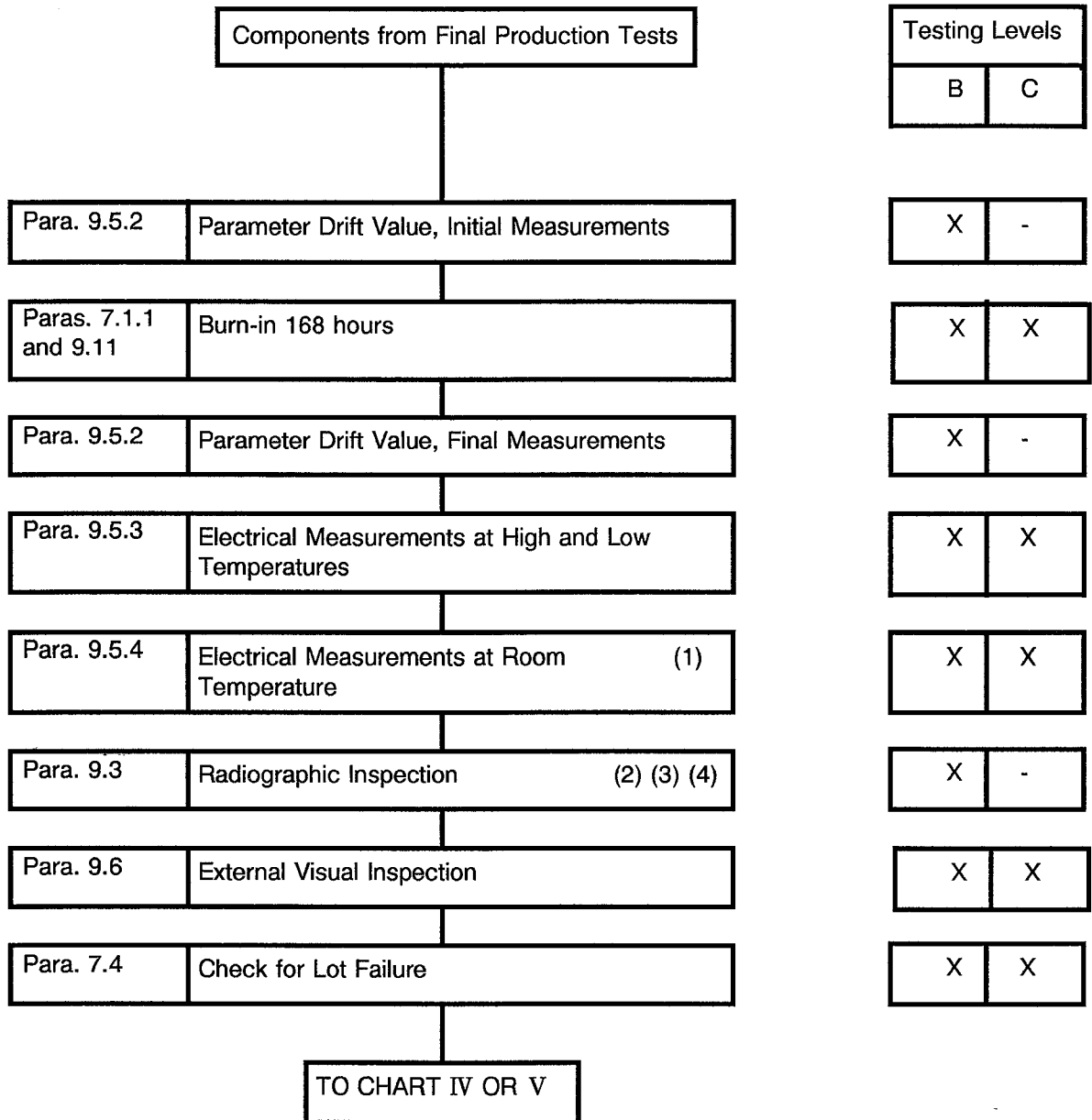




CHART III - BURN-IN AND ELECTRICAL MEASUREMENTS

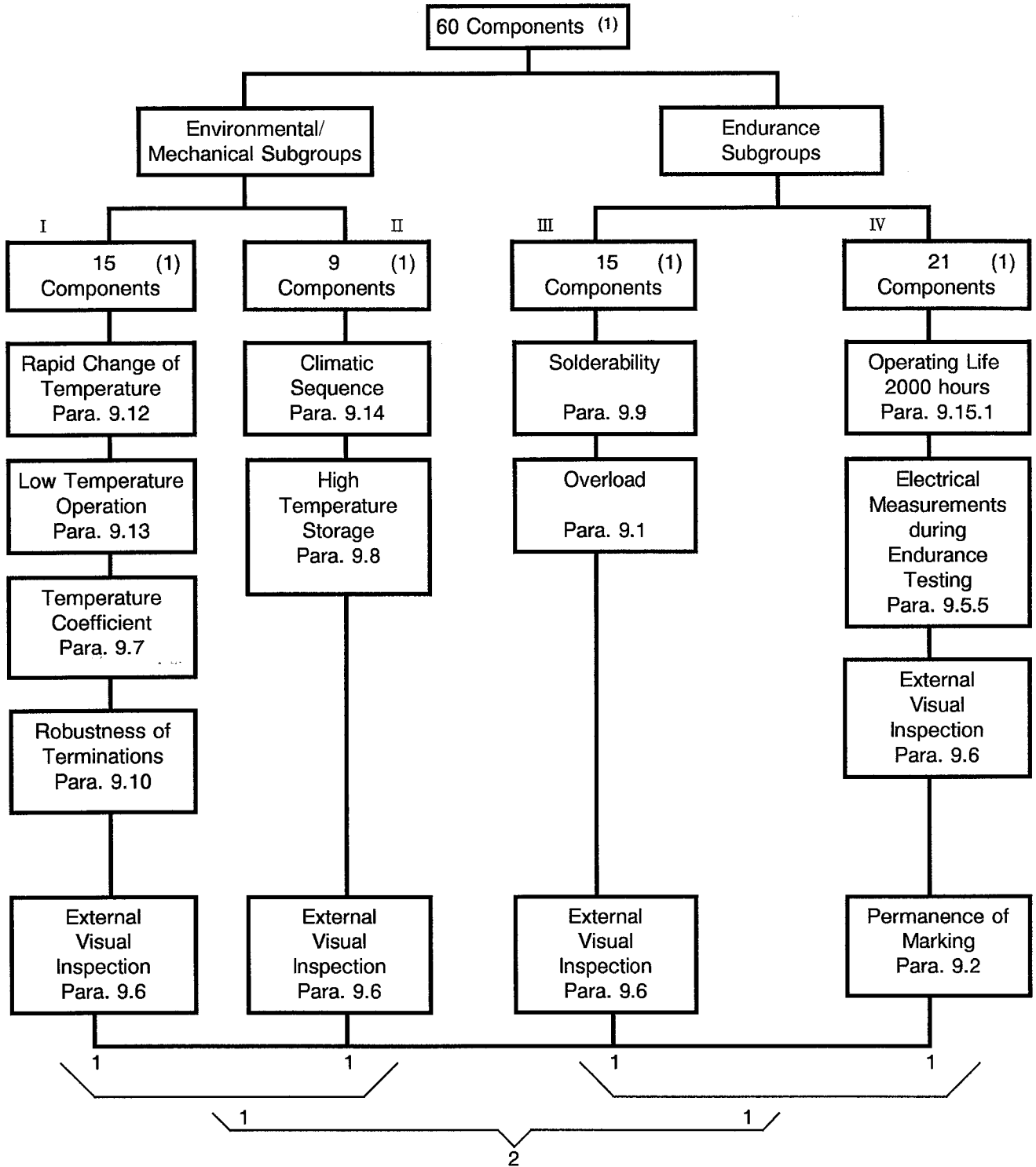


NOTES

1. The measurements of parameters for the purpose of drift value measurements need not be repeated for electrical measurements at room temperature.
2. Radiographic Inspection may be performed at any point during the test sequence shown in this Chart.
3. Radiographic Inspection rejects not to be counted for lot failure.
4. Unless otherwise specified in the Detail Specification.



CHART IV - QUALIFICATION TESTS



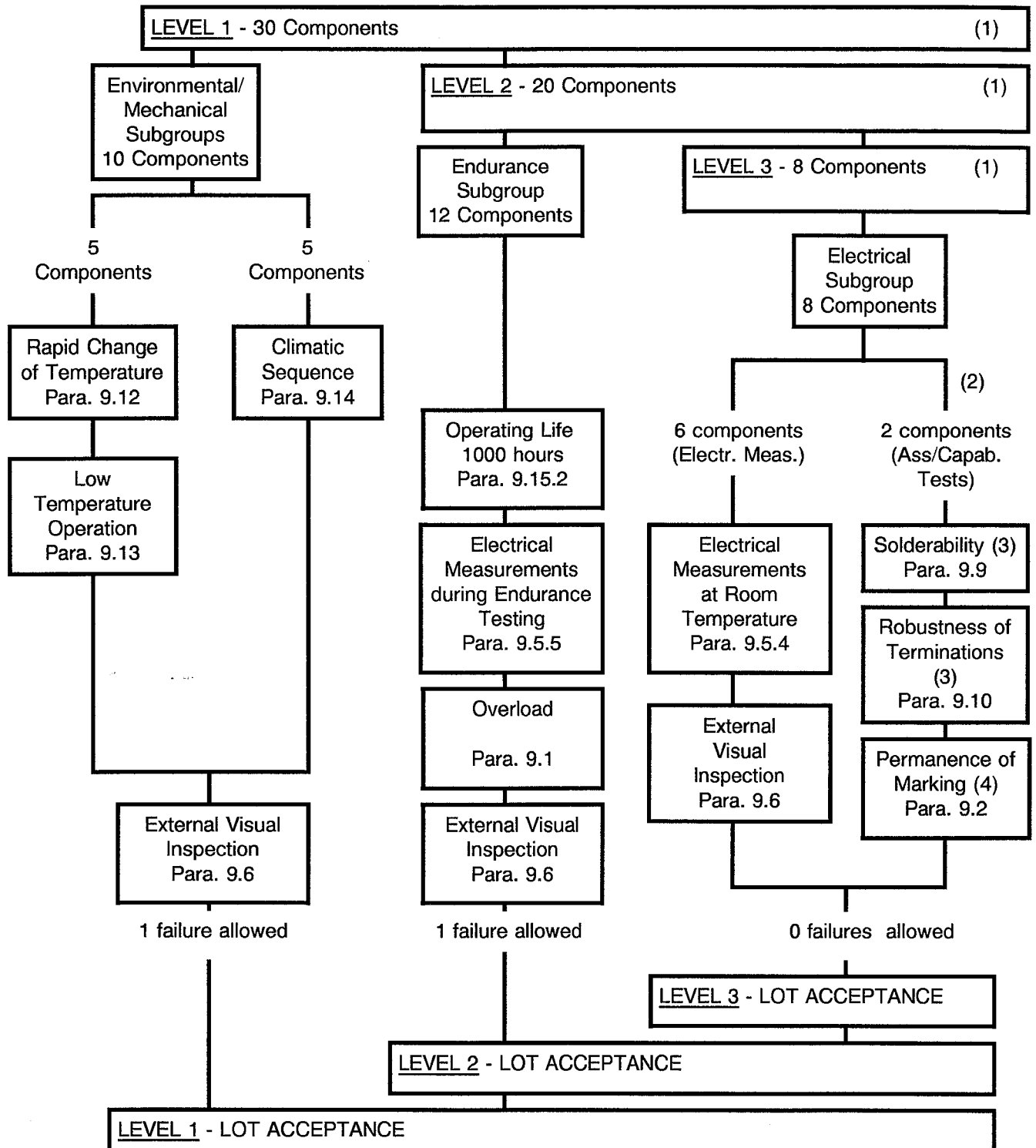
Total allowable number of failed components: 2.

NOTES

1. For distribution within the subgroups, see Para. 8.1.2.



CHART V - LOT ACCEPTANCE TESTS



NOTES

1. For distribution within the subgroups, see Para. 8.2.2.
2. Post-burn-in electrical rejects may be used for this test.
3. Not to be performed if done during special in-process controls.
4. If Solderability and Robustness of Terminations have been performed during Special In-process Controls, then Permanence of Marking may be performed on 2 samples after Electrical Measurements at Room Temperature.

**9. TEST METHODS AND PROCEDURES**

If a Manufacturer elects to eliminate or modify a test method or procedure, the Manufacturer is still responsible for delivering components that meet all of the performance, quality and reliability requirements defined in this specification and the Detail Specification.

Documentation supporting the change shall be approved by the Qualifying Space Agency and retained by the Manufacturer. It shall be copied, when requested, to the Qualifying Space Agency.

The change shall be specified in the Detail Specification and in the P.I.D.

9.1 OVERLOAD**9.1.1 Mounting**

The flexible heaters shall be suspended by their terminal leads in still air with no circulation other than that caused by the heat of the flexible heaters being operated.

The ambient temperature shall be between +15 and +35 °C.

Each layer of double layer heaters shall be tested separately, each for the times specified hereunder.

Resistors of multiple resistor heaters shall be tested simultaneously, unless otherwise specified by the Orderer.

9.1.2 Procedure**9.1.2.1 Final Production Tests**

The flexible heaters shall be tested with a power of 1.5 times the rated power for a period of 1 minute minimum.

9.1.2.2 Qualification and Lot Acceptance Tests**(a) Initial Measurements**

The resistance shall be measured as specified in Para. 9.5.1.1.

(b) Test Conditions

The flexible heaters shall be tested with a power of 1.5 times the rated power for a period of 30 minutes minimum.

(c) Recovery and Final Measurement

After a recovery period not less than 1 hour and not more than 2 hours the resistance shall be measured. The change in resistance compared to the value measured in (a) above shall not exceed the value prescribed in Table 6 of the Detail Specification.

9.2 PERMANENCE OF MARKING

In accordance with ESA/SCC Basic Specification No. 24800.

9.3 RADIOGRAPHIC INSPECTION

The flexible heaters shall be radiographed in the plane perpendicular to the surface in accordance with the requirements of ESA/SCC Basic Specification No. 20900.

9.4 DIMENSION CHECK

In accordance with ESA/SCC Basic Specification No. 20500 and the Detail Specification. To be performed on 5 samples only.

If 1 failure occurs, the complete lot shall be checked.



9.5 ELECTRICAL MEASUREMENTS

9.5.1 General

Electrical measurements and methods shall be as follows.

9.5.1.1 Resistance

Measurement of resistance shall be made by using a direct voltage of small magnitude for as short a time as practicable so that the temperature does not rise appreciably during measurement.

The resistance of terminal leads attached to the flexible heaters shall be calculated and subtracted from the actual measurement. The terminal lead resistance shall be calculated from data found in the applicable wire and cable Generic and Detail Specifications. Additionally, for high and low temperatures and Temperature Coefficient measurements, the flexible heaters and the whole length of their terminal leads shall be placed inside the temperature chamber. In this case, the terminal lead resistance, adjusted for temperature coefficient resistance, shall be subtracted from the actual measurement.

In the event of conflicting results, attributable to such test voltages, the voltage specified in the following table shall be used for reference purposes:-

Rated Resistance (R_n) (Ω)	Measuring Voltage V(+0-10)%
less than 10	0.1 (Note 1)
10 to 99	0.3
100 to 999	1
1000 to 9999	3

NOTES

- The accuracy of the measuring equipment shall be such that the error does not exceed 10% of the tolerance. Where the measurement forms part of a test sequence, it shall be possible to measure a change in resistance with an error not exceeding 10% of the maximum change permitted for that test. The resistance limits at $+22 \pm 3$ °C are given in Table 2 of the Detail Specification.

9.5.1.2 Insulation Resistance

9.5.1.2.1 Mounting

The flexible heaters shall be clamped between 2 conducting plates connected together.

9.5.1.2.2 Procedure

The insulation resistance shall be measured with a direct voltage of $500 \pm 50V$. The measurement shall be performed between all terminations of the heater connected together as one pole and the mounting device as the other pole; for heaters with more than one resistor, the measurement shall also be performed between each resistor, with each resistor having both terminations connected together to form one pole.

The voltage shall be applied for 1 minute or such shorter time as is necessary to



obtain a stable reading. The insulation resistance shall be read at the end of that period and shall not be less than that prescribed in the Detail Specification.

9.5.1.3 Voltage Proof

9.5.1.3.1 Mounting

The flexible heaters shall be clamped between 2 conducting plates connected together.

9.5.1.3.2 Procedure

A voltage as specified in Table 2 of the Detail Specification shall be applied for a period of 60 ± 5 seconds between all terminations of the heater connected together as one pole and the mounting device as the other pole; for heaters with more than one resistor, the measurement shall also be performed between each resistor, with each resistor having both terminations connected together to form one pole. The voltage shall be applied gradually at a rate of approximately 100V/second.

9.5.2 Parameter Drift Value Measurements

At each of the relevant data points for components of testing level 'B', measurements shall be made of all parameters listed in Table 4 of the Detail Specification. All values obtained shall be recorded against serial numbers and the parameter drift calculated.

9.5.3 Electrical Measurements at High and Low Temperatures

For components of testing levels 'B' and 'C', the electrical measurements at high and low temperatures shall be made in accordance with Table 3 of the Detail Specification. Where sample testing is applied, note the requirements of Para. 8.2.3(b). For testing level 'B', all values obtained shall be recorded against serial numbers.

9.5.4 Electrical Measurements at Room Temperature

For components of testing levels 'B' and 'C', the measurements of electrical characteristics shall be made in accordance with Table 2 of the Detail Specification. Where sample testing is applied, note the requirements of Para. 8.2.3(b). For testing level 'B', all values obtained shall be recorded against serial numbers.

9.5.5 Electrical Measurements during Endurance Testing

At each of the relevant data points specified for endurance testing, measurements shall be made of all parameters listed in Table 6 of the Detail Specification. All values obtained shall be recorded against serial numbers and the parameter drift calculated, if required.

9.6 EXTERNAL VISUAL INSPECTION

In accordance with ESA/SCC Basic Specification No. 20500. The heater surfaces shall be free of cuts or abrasion. The heaters shall not exhibit bubbles or delamination.

9.7 TEMPERATURE COEFFICIENT

The flexible heaters shall be dried as prescribed in the Detail Specification by applying either Procedure I or II as follows.

9.7.1 Procedure I

For 24 ± 4 hours in an oven at a temperature of $+55 \pm 2$ °C and with a relative humidity not exceeding 20%.

**9.7.2 Procedure II**

For 96 ± 4 hours in an oven at $+100 \pm 5$ °C. The flexible heaters shall then be allowed to cool in a desiccator, using a suitable desiccant such as activated alumina or silica gel, and be kept therein from the time of removal from the oven until the beginning of the test.

9.7.3 Test Procedure

The flexible heaters shall be maintained at each of the following temperatures in turn:-

- (a) $+22 \pm 3$ °C.
- (b) lower category ± 3 °C.
- (c) $+22 \pm 3$ °C.
- (d) upper category ± 2 °C.
- (e) $+22 \pm 3$ °C.

Within 10 to 15 minutes after the flexible heaters have reached thermal stability, resistance measurements shall be made at each of the above mentioned temperatures, using the method specified in Para. 9.5.1.1. The temperature of the flexible heaters at the time of measurement shall be recorded. The error of temperature measurement shall not exceed 1°C. Thermal stability will have been reached when no further change in resistance is observed between two successive measurements taken at 15 minute intervals. The Temperature Coefficient of Resistance between +22°C and each of the other specified temperatures shall be calculated from the following formula:-

Temperature Coefficient of Resistance in $10^{-6}/^{\circ}\text{C}$:

$$10^6 \frac{\Delta R}{R \cdot \Delta T} \cdot K,$$

Where 'K' = $\frac{\text{difference between nominal specified temperatures}}{\text{difference between recorded temperatures}}$

ΔT = difference between recorded temperatures,

and where, if the resistances recorded above are designated Ra, Rb, Rc, Rd and Re, 'R', and ' ΔR ' are given as shown in the Table below.

	Lower Category Temperature	Upper Category Temperature
R	$1/2 (R_a + R_c)$	$1/2 (R_c + R_e)$
ΔR	$R_b - R$	$R_d - R$

The Temperature Coefficient, determined as described above, shall not exceed the value prescribed in the Detail Specification for the appropriate category temperature. Where the resistance value is greater than 10Ω but less than 20Ω , the Temperature Coefficient shall not exceed twice the value prescribed in the Detail Specification.

NOTES

1. The Temperature Coefficient is not specified for resistance values of less than 10Ω due to difficulty of accurate measurement.

**9.8 HIGH TEMPERATURE STORAGE**

(a) **Duration:** 2000 hours.

(b) **Method of Mounting**

The flexible heaters shall be suspended freely by their terminal leads.

(c) **Test Conditions**

As specified in the Detail Specification.

For end-point data measurements, the flexible heaters shall be allowed to cool at room temperature for not less than 1 hour and not more than 2 hours.

(d) **Data Points**

Measurements at end-points in accordance with Table 6 of the Detail Specification at 0 and 2000 ± 48 hours.

In the case where Table 6 specifies "changes", the drift shall always be related to the 0-hour measurement.

9.9 SOLDERABILITY**9.9.1 Procedure**

The terminal leads of flexible heaters shall be subjected to Test 'Ta' of IEC Publication No. 68-2-20, using Method 1 (Solder Bath).

9.9.2 Final Examination

Inspection shall be carried out under adequate light with the assistance of a magnifier capable of giving a magnification of 4x to 10x. The dipped surface shall be covered with a smooth and bright solder coating with no more than small amounts of scattered imperfections such as pin-holes or un-wetted or de-wetted areas. These imperfections shall not be concentrated in one area.

9.10 ROBUSTNESS OF TERMINATIONS

The flexible heaters shall be subjected to Test 'Ua 1' of IEC Publication No. 68-2-21.

9.10.1 Initial Measurement

The resistance shall be measured as specified in Para. 9.5.1.1.

9.10.2 Procedure

The strength and duration of the pull are given in the Detail Specification.

9.10.3 Final Measurement

The resistance shall be measured. The change in resistance compared to the value measured in Para. 9.10.1 shall not exceed the value prescribed in Table 6 of the Detail Specification.

9.11 BURN-IN

The method for mounting heaters and the test set-up shall be as specified in Para. 9.15.1(b) and (c).



The test shall be conducted in accordance with IEC Publication No. 115-1, Clause 4.25. Each layer of double layer heaters shall be tested successively for 84 hours. Resistors of multiple resistor single layer heaters shall be tested simultaneously.

9.12 RAPID CHANGE OF TEMPERATURE

9.12.1 Initial Measurements

9.12.1.1 Final Production Tests

None.

9.12.1.2 Qualification and Lot Acceptance Tests

The resistance shall be measured as specified in Para. 9.5.1.1.

9.12.2 Procedure and Recovery

The flexible heaters shall be suspended by their terminal leads and submitted to Test 'Na' of IEC Publication No. 68-2-14 for the number of cycles specified hereunder. The duration of exposure at each of the storage temperature extremes given in Table 1(b) of the Detail Specification shall be 15 minutes.

The flexible heaters shall then remain under standard atmospheric conditions for recovery for not less than 1 hour and not more than 2 hours.

9.12.2.1 Final Production Tests

The number of cycles shall be 10. During the 10 exposures to high temperature, electrical continuity shall be checked.

9.12.2.2 Qualification and Lot Acceptance Tests

The number of cycles shall be 500.

9.12.3 Final Measurements

9.12.3.1 Final Production Tests

None.

9.12.3.2 Qualification and Lot Acceptance Tests

The resistance shall be measured. The change in resistance compared to the value measured in Para. 9.12.1.2 shall not exceed the limit prescribed in Table 6 of the Detail Specification.

9.13 LOW TEMPERATURE OPERATION

9.13.1 Initial Measurement

The resistance shall be measured as specified in Para. 9.5.1.1.

9.13.2 Procedure and Recovery

The flexible heaters shall be placed in a chamber at the lower category temperature. After 1 hour of stabilisation at this temperature, the flexible heaters shall be tested with rated power for 45 minutes.

Each layer of double layer heaters shall be tested separately for 45 minutes each.



Resistors of multiple resistor heaters shall be tested simultaneously, unless otherwise specified by the Orderer.

Commencing 15 minutes after removal of power, the heaters shall be brought to 22 ± 3 °C in a period not exceeding 8 hours.

9.13.3 Final Measurements

The resistance shall be measured after approximately 24 hours at 22 ± 3 °C. The resistance and the insulation resistance shall then be measured. The change in resistance compared to the value measured in Para. 9.13.1 shall not exceed the value prescribed in Table 6 of the Detail Specification. The insulation resistance shall not be less than that prescribed in Table 6 of the Detail Specification.

A voltage proof test shall be performed in accordance with Para. 9.5.1.3 and there shall be no evidence of breakdown or flash-over.

9.14 CLIMATIC SEQUENCE

9.14.1 Initial Measurement

The resistance shall be measured as specified in Para. 9.5.1.1.

9.14.2 Dry Heat

The flexible heaters shall be subjected to Test 'Ba' of IEC Publication No. 68-2-2 at the upper category temperature for 2 hours, taking into account the following deviation:-

The flexible heaters shall be removed from the chamber and be exposed to standard atmospheric conditions for recovery, for not less than 1 hour.

9.14.3 Damp Heat (Accelerated) First Cycle

The flexible heaters, suspended by their terminal leads, shall be subjected to Test 'Db', Severity a, Variant 2, of IEC Publication No. 68-2-30, for one cycle of 24 hours. After recovery, the flexible heaters shall be immediately subjected to the cold test.

9.14.4 Cold Test

The flexible heaters shall be subjected to Test 'Ad' of IEC Publication No. 68-2-1 at the lower category temperature. After 1 hour of stabilisation at this temperature, the flexible heaters shall be tested with rated power for 45 minutes.

Double layer heaters shall be tested one layer after the other.

Resistors of multiple resistor heaters shall be tested simultaneously, unless otherwise specified by the Orderer.



The flexible heaters shall then be removed from the chamber and exposed to standard atmospheric conditions for recovery for not less than 4 hours.

9.14.5 Low Air Pressure

The flexible heaters, tested with rated power, shall be subjected to Test 'M' of IEC Publication No. 68-2-13, using a pressure of 20 ± 1 mbar.

Each layer of double layer heaters shall be tested separately.

Resistors of multiple resistor heaters shall be tested simultaneously, unless otherwise specified by the Orderer.

		<p>ESA/SCC Generic Specification No. 4009</p>	<p>PAGE 28 ISSUE 3</p>
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The test shall be performed at a temperature between + 15 and + 35 °C.

The duration of the test shall be 1 hour.

9.14.6 Damp Heat (Accelerated) Remaining Cycles

The flexible heaters, suspended by their terminal leads, shall be subjected to Test 'Db', Severity a, Variant 2, of IEC Publication No. 68-2-30 for 5 cycles of 24 hours.

9.14.7 D.C. Load

At the end of the conditioning period, the flexible heaters shall be subjected to the standard atmospheric conditions for recovery. The time of transfer shall be as brief as possible and in any case shall not exceed 5 minutes.

At 30 ±5 minutes after removal from the chamber after damp heat cyclic testing, the flexible heaters shall be tested at rated power for 1 minute. Each layer of double layer heaters shall be tested separately for 1 minute each.

Resistors of multiple resistor heaters shall be tested simultaneously, unless otherwise specified by the Orderer.

The flexible heaters shall then be subjected to the standard atmospheric conditions for recovery for not less than 1 hour and not more than 2 hours.

9.14.8 Final Measurement

The resistance and the insulation resistance shall then be measured. The change in resistance compared to the value measured in Para. 9.14.1 shall not exceed the value prescribed in Table 6 of the Detail Specification. The insulation resistance shall not be less than that prescribed in Table 6 of the Detail Specification.

A voltage proof test shall be performed in accordance with Para. 9.5.1.3 and there shall be no evidence of breakdown or flash-over.

9.15 OPERATING LIFE

9.15.1 Operating Life during Qualification Testing

(a) **Duration:** 2000 hours.

Each layer of double layer heaters shall be tested successively for 1 000 hours.

(b) **Method of Mounting**

The flexible heaters shall be freely suspended and connected by their terminal leads. They shall be positioned in such a way that the heat from one heater does not unduly influence the temperature of any other heater. There shall be no undue draught over the flexible heaters. Only natural convection resulting from the operating flexible heaters may occur.

(c) **Test Conditions**

As specified in Table 5 of the Detail Specification.

The voltage (d.c. or full-wave rectified a.c. with ripple less than 5%) shall be increased until the following occurs:

- The rated power density is reached, or
- The temperature of the heaters reaches the maximum operating temperature.



The voltage shall then be applied in cycles of 1.5 hours 'ON' and 0.5 hours 'OFF' throughout the test. The 0.5 hour 'OFF' periods are included in the total test duration.

Resistors of multiple resistor single layer heaters shall be tested simultaneously.

For intermediate and end-point data measurements, the flexible heaters shall be allowed to cool at room temperature for not less than 1 hour and not more than 2 hours. The measurements shall take place at the end of the 0.5 hour "off" period.

After intermediate measurements, the flexible heaters shall be returned to the test conditions. The interval between the removal of any heater from the load and its return to the conditions of the test shall not exceed 12 hours.

(d) Intermediate Data Points

Measurements at intermediate points in accordance with Table 6 of the Detail Specification at 0 and 1000 ± 48 hours.

In the case where Table 6 specifies "changes", the drift shall always be related to the 0-hour measurement.

(e) End Data Points

Measurements at end-points in accordance with Table 6 of the Detail Specification at 0 and 2000 ± 48 hours.

In the case where Table 6 specifies "changes", the drift shall always be related to the 0-hour measurement.

9.15.2 Operating Life during Lot Acceptance Testing

(a) Duration: 1000 hours.

Each layer of double layer heaters shall be tested successively for 500 hours.

(b) Method of Mounting

The flexible heaters shall be freely suspended and connected by their terminal leads. They shall be positioned in such a way that the heat from one heater does not unduly influence the temperature of any other heater. There shall be no undue draught over the flexible heaters. Only natural convection resulting from the operating flexible heaters may occur.

(c) Test Conditions

As specified in Table 5 of the Detail Specification.



The voltage (d.c. or full-wave rectified a.c. with ripple less than 5%) shall be increased until the following occurs:

- The rated power density is reached, or
- The temperature of the heaters reaches the maximum operating temperature.

The voltage shall then be applied in cycles of 1.5 hours 'ON' and 0.5 hours 'OFF' throughout the test. The 0.5 hour 'OFF' periods are included in the total test duration.

Resistors of multiple resistor single layer heaters shall be tested simultaneously.

For end-point data measurements, the flexible heaters shall be allowed to cool at room temperature for not less than 1 hour and not more than 2 hours. The measurements shall take place at the end of the 0.5 hour "off" period.

		ESA/SCC Generic Specification No. 4009	PAGE 30 ISSUE 3
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(d) **Data Points**

Measurements at end-points in accordance with Table 6 of the Detail Specification at 0 and 1000 ± 48 hours.

In the case where Table 6 specifies "changes", the drift shall always be related to the 0-hour measurement.

**10. DATA DOCUMENTATION****10.1 GENERAL**

For the qualification approval records and with each component delivery, a data documentation package is required. Depending on the testing level and lot acceptance level specified for the component, this package shall be compiled from:-

- (a) Cover sheet (or sheets).
- (b) List of equipment (testing and measuring).
- (c) List of test references.
- (d) Special in-process control test data (when required by the Detail Specification).
- (e) Final production test data (Chart II) (but see Para. 10.6).
- (f) Burn-in and electrical measurement data (Chart III).
- (g) Qualification test data (Chart IV).
- (h) Lot acceptance test data (Chart V) (when applicable).
- (i) Failed component list (see Paras. 7.3 and 8.4) and failure analysis report (see Para. 8.4).
- (j) Certificate of Conformity.
- (k) Radiographic inspection photographs.

Items (a) to (k) inclusive shall be grouped, preferably as subpackages and, for identification purposes, each page shall include the following information:

- ESA/SCC Component number.
- Manufacturer's name.
- Lot identification.
- Date of establishment of the document.
- Page number.


10.1.1 Qualification Approval

In the case of qualification approval, the items listed in Para. 10.1 (a) to (k) less item (h) are required.

10.1.2 Testing Level 'B'**10.1.2.1 Qualified Components**

For deliveries of qualified components, the following documentation shall be supplied:-

- (a) Cover sheet (if all of the information is not included on the Certificate of Conformity).
- (b) Certificate of Conformity (including range of delivered serial numbers).
- (c) Attributes record of measurements, tests and inspections performed in Chart II, Chart III (including PDA figure) and Chart V (where applicable).
- (d) Failed components list.

	<p style="text-align: center;">ESA/SCC Generic Specification No. 4009</p>	<p style="text-align: center;">Rev. 'B'</p>	<p style="text-align: center;">PAGE 31A ISSUE 3</p>
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10.1.2.2 Unqualified Components

For deliveries of unqualified components, the documentation to be supplied shall be in accordance with Para. 10.1.2.1 plus the following:-

- (a) Read and record data from Chart III.
- (b) Special in-process control data (where applicable).
- (c) Failure analysis report on failed components.

10.1.3 Testing Level 'C'

10.1.3.1 Qualified Components

For deliveries of qualified components, the following documentation shall be supplied:-

- (a) Certificate of Conformity.



10.1.3.2 Unqualified Components

For deliveries of unqualified components, the documentation to be supplied shall be in accordance with Para. 10.1.3.1 plus the following:-

- (a) Cover sheet (if all of the information is not included on the Certificate of Conformity).
- (b) Attributes record of all measurements, tests and inspections performed in Charts II, III and V (when applicable).
- (c) Failed components list (including Failure Analysis Report).
- (d) Special in-process control data (when applicable).

10.1.4 Data Retention/Data Access

If not delivered, all data shall be retained by the Manufacturer for a minimum of 5 years during which time it shall be available to the Qualifying Space Agency and the Orderer, if requested, for review. The Manufacturer shall deliver variables Data/Reports to the Orderer if required by the Purchase Order.

 	<p style="text-align: center;">ESA/SCC Generic Specification No. 4009</p>	<p style="text-align: center;">Rev. 'A'</p>	<p>PAGE 32 ISSUE 3</p>
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10.2 COVER SHEET(S)

The cover sheet(s) of the data documentation package shall include as a minimum:-

- (a) Reference to the Detail Specification, including issue and date.
- (b) Reference to the applicable ESA/SCC Generic Specification, including issue and date.
- (c) Component type and number.
- (d) Lot identification.
- (e) Range of delivered serial numbers (for components of testing level 'B').
- (f) Number of purchase order.
- (g) Information relative to any additions to this specification and/or the Detail Specification.
- (h) Manufacturer's name and address.
- (i) Location of the manufacturing plant.
- (j) Signature on behalf of Manufacturer.
- (l) Total number of pages of the data package.

10.3 LIST OF EQUIPMENT USED

A list of equipment used for tests and measurements shall be prepared, if not in accordance with the data given in the Process Identification Document (P.I.D.). Where applicable, this list shall contain inventory number, Manufacturer's type number, serial number, etc. This list shall indicate for which tests such equipment was used.

10.4 LIST OF TEST REFERENCES

This list shall include all Manufacturer's references or codes which are necessary to correlate the test data provided with the applicable tests specified in the tables of the Detail Specification.

10.5 SPECIAL IN-PROCESS CONTROL DATA


As specified in the Detail Specification.

10.6 FINAL PRODUCTION TEST DATA (CHART II)

A test result summary shall be compiled showing the total number of components submitted to, and the total number rejected after, each of the following tests:

- Rapid change of temperature (Para. 9.12).
- Overload (Para. 9.1).
- Electrical measurements at room temperature (Para. 9.5.4).
- External visual inspection (Para. 9.6).
- Dimension check (Para. 9.4).

The final production test data shall form an integral part of the data documentation package, but it is not a mandatory requirement that it be delivered with the qualification lot or delivery lot. However, the data package to be delivered shall contain the information as detailed in Paras. 10.1.2 and 10.1.3 or at least shall contain a list of final production tests actually performed and a certification that the data is available for review.

	<p style="text-align: center;">ESA/SCC Generic Specification No. 4009</p>	<p style="text-align: center;">Rev. 'A'</p>	<p>PAGE 33 ISSUE 3</p>
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10.7 BURN-IN AND ELECTRICAL MEASUREMENT DATA (CHART III)

10.7.1 Testing Level 'B'

For components of testing level 'B', all data shall refer to the relevant serial numbers. Against these serial numbers, data shall be recorded of the following:-

- (a) 0-hour measurement for burn-in.
- (b) 168-hour measurement for burn-in.
- (c) Delta values after burn-in.
- (d) Values obtained during measurements at high and low temperatures (Table 3 of the Detail Specification).
- (e) Values obtained during measurements of electrical characteristics (Table 2 of the Detail Specification).
- (f) Failures during external visual inspection.
- (g) Photographs from radiographic inspection, including those of reject components.

10.7.2 Testing Level 'C'

For components of testing level 'C', a test result summary (i.e. the total number of components subjected to, and the total number rejected from, each of the tests and inspections) shall be prepared.

10.8 QUALIFICATION TEST DATA (CHART IV)

All data shall be referenced to the relevant serial numbers. Detailed records shall be provided of the components submitted to each test in each of the subgroups and of those rejected. Detailed data shall be provided of all electrical measurements made in accordance with Tables 2 and 6 of the Detail Specification, as and where applicable.

10.9 LOT ACCEPTANCE TEST DATA (CHART V)

10.9.1 Testing Level 'B'

All data shall be referenced to the relevant serial numbers. Detailed records shall be provided of the components submitted to each test in each of the subgroups (as relevant to the lot acceptance level) and of those rejected.



Detailed data shall be provided of all electrical measurements made in accordance with Table 6 of the Detail Specification, as and where applicable.

10.9.2 Testing Level 'C'

A test result summary (i.e. the total number of components submitted to, and and the total number rejected from, each of the tests and inspections) as relevant to the lot acceptance level shall be provided.

In the case of lot acceptance 2 testing, all data in respect of electrical measurements made in accordance with Table 6 of the Detail Specification shall be referenced to the relevant serial numbers (see Para. 8.2.4(a)).

In the case of lot acceptance 1 testing, all data in respect of electrical measurements made in accordance with Table 6 of the Detail Specification shall be referenced to the relevant serial numbers (see Para. 8.2.5(a)).

 	<p style="text-align: center;">ESA/SCC Generic Specification No. 4009</p>	<p style="text-align: center;">Rev. 'A'</p>	<p>PAGE 34 ISSUE 3</p>
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10.10 FAILED COMPONENT LIST AND FAILURE ANALYSIS REPORT

The failed component list and failure analysis report shall provide full details of:-

- (a) The reference number and description of the test or measurement performed as defined in this specification and/or the Detail Specification.
- (b) The serial number (if applicable) of the failed component.
- (c) The failed parameter and the failure mode of the component.
- (d) Detailed failure analysis, if requested.

10.11 CERTIFICATE OF CONFORMITY

A Certificate of Conformity shall be established as defined in ESA/SCC Basic Specification No. 20100.

11. DELIVERY

For qualification approval, the disposition of the qualification test lot and its related documentation shall be as specified in ESA/SCC Basic Specification No. 20100 and the relevant paragraphs of Section 10 of this specification.

For procurement, for each order, the items forming the delivery are:-

- (a) The delivery lot.
- (b) The components used for lot acceptance testing, (when applicable), but not forming part of the delivery lot (see Paras. 8.2.3(d), 8.2.4(b) and 8.2.5(b)).
- (c) The relevant documentation in accordance with the requirements of Section 10 of this specification.

In the case of a component for which a valid qualification approval is in force, all data of all components submitted to LA1 and LA2 testing shall also be copied, when requested, to the relevant Qualifying Space Agency.

12. PACKAGING AND DESPATCH

The packaging and despatch of components to this specification shall be in accordance with the requirements of ESA/SCC Basic Specification No. 20600.

ANNEXE I

LTPD SAMPLING PLAN LOT SIZES GREATER THAN 200 DEVICES

Minimum size of sample to be tested to assure with a 90% confidence that a lot whose Percent Defective equals the specified LTPD is not accepted (single sample).

Max. Percent Defective (LTPD) or λ	50	30	20	15	10	7	5	3	2	1.5	1	0.7	0.5	0.3	0.2	0.15	0.1
Acceptance Number (c) ($r = c + 1$)	MINIMUM SAMPLE SIZES (FOR DEVICE-HOURS REQUIRED FOR LIFE TEST, MULTIPLY BY 1000)																
0	5 (1.03)	8 (0.64)	11 (0.46)	15 (0.34)	22 (0.23)	32 (0.16)	45 (0.11)	76 (0.07)	116 (0.04)	153 (0.03)	231 (0.02)	328 (0.02)	461 (0.01)	767 (0.007)	1152 (0.005)	1534 (0.003)	2303 (0.002)
1	8 (4.4)	13 (2.7)	18 (2.0)	25 (1.4)	38 (0.94)	55 (0.65)	77 (0.46)	129 (0.28)	195 (0.18)	258 (0.14)	390 (0.09)	555 (0.06)	778 (0.045)	1296 (0.027)	1946 (0.018)	2592 (0.013)	3891 (0.009)
2	11 (7.4)	18 (4.5)	25 (3.4)	34 (2.4)	52 (1.6)	75 (1.1)	105 (0.78)	176 (0.47)	266 (0.31)	354 (0.23)	533 (0.15)	759 (0.11)	1065 (0.080)	1773 (0.045)	2662 (0.031)	3547 (0.022)	5323 (0.015)
3	13 (10.5)	22 (6.2)	32 (4.4)	43 (3.2)	65 (2.1)	94 (1.5)	132 (1.0)	221 (0.62)	333 (0.41)	444 (0.31)	668 (0.20)	953 (0.14)	1337 (0.10)	2226 (0.062)	3341 (0.041)	4452 (0.031)	6681 (0.018)
4	16 (12.3)	27 (7.3)	38 (5.3)	52 (3.9)	78 (2.6)	113 (1.8)	158 (1.3)	265 (0.75)	398 (0.50)	531 (0.37)	798 (0.25)	1140 (0.17)	1599 (0.12)	2663 (0.074)	3997 (0.049)	5327 (0.037)	7994 (0.025)
5	19 (13.8)	31 (8.4)	45 (6.0)	60 (4.4)	91 (2.9)	131 (2.0)	184 (1.4)	308 (0.85)	462 (0.57)	617 (0.42)	927 (0.28)	1323 (0.20)	1855 (0.14)	3090 (0.085)	4638 (0.056)	6181 (0.042)	9275 (0.028)
6	21 (15.6)	35 (9.4)	51 (6.6)	68 (4.9)	104 (3.2)	149 (2.2)	209 (1.6)	349 (0.94)	528 (0.62)	700 (0.47)	1054 (0.31)	1503 (0.22)	2107 (0.155)	3509 (0.093)	5267 (0.062)	7019 (0.047)	10533 (0.031)
7	24 (16.6)	39 (10.2)	57 (7.2)	77 (5.3)	116 (3.5)	166 (2.4)	234 (1.7)	390 (1.0)	589 (0.67)	783 (0.51)	1178 (0.34)	1680 (0.24)	2355 (0.17)	3922 (0.101)	5886 (0.067)	7845 (0.051)	11771 (0.034)
8	26 (18.1)	43 (10.9)	63 (7.7)	85 (5.6)	128 (3.7)	184 (2.6)	258 (1.8)	431 (1.1)	648 (0.72)	864 (0.54)	1300 (0.36)	1854 (0.25)	2599 (0.18)	4329 (0.108)	6498 (0.072)	8660 (0.054)	12995 (0.036)
9	28 (19.4)	47 (11.5)	69 (8.1)	93 (6.0)	140 (3.9)	201 (2.7)	282 (1.9)	471 (1.2)	709 (0.77)	945 (0.58)	1421 (0.38)	2027 (0.27)	2842 (0.19)	4733 (0.114)	7103 (0.077)	9468 (0.057)	14206 (0.038)
10	31 (19.9)	51 (12.1)	75 (8.4)	100 (6.3)	152 (4.1)	218 (2.9)	306 (2.0)	511 (1.2)	770 (0.80)	1025 (0.60)	1541 (0.40)	2199 (0.28)	3082 (0.20)	5133 (0.120)	7704 (0.080)	10268 (0.060)	15407 (0.040)
11	33 (21.0)	54 (12.8)	83 (8.3)	111 (6.2)	166 (4.2)	238 (2.9)	332 (2.1)	555 (1.2)	832 (0.83)	1109 (0.62)	1664 (0.42)	2378 (0.29)	3323 (0.21)	5546 (0.12)	8319 (0.083)	11092 (0.062)	16638 (0.042)
12	36 (21.4)	59 (13.0)	89 (8.6)	119 (6.5)	178 (4.3)	254 (3.0)	356 (2.2)	594 (1.3)	890 (0.86)	1187 (0.65)	1781 (0.43)	2544 (0.3)	3562 (0.22)	5936 (0.13)	8904 (0.086)	11872 (0.065)	17808 (0.043)
13	38 (22.3)	63 (13.4)	95 (8.9)	126 (6.7)	190 (4.5)	271 (3.1)	379 (2.26)	632 (1.3)	948 (0.89)	1264 (0.67)	1896 (0.44)	2709 (0.31)	3793 (0.22)	6321 (0.134)	9482 (0.089)	12643 (0.067)	18964 (0.045)
14	40 (23.1)	67 (13.8)	101 (9.2)	134 (6.9)	201 (4.6)	288 (3.2)	403 (2.3)	672 (1.4)	1007 (0.92)	1343 (0.69)	2015 (0.46)	2878 (0.32)	4029 (0.23)	6716 (0.138)	10073 (0.092)	13431 (0.069)	20146 (0.046)
15	43 (23.3)	71 (14.1)	107 (9.4)	142 (7.1)	213 (4.7)	305 (3.3)	426 (2.36)	711 (1.41)	1066 (0.94)	1422 (0.71)	2133 (0.47)	3046 (0.33)	4265 (0.235)	7108 (0.141)	10662 (0.094)	14216 (0.070)	21324 (0.047)
16	45 (24.1)	74 (14.0)	112 (9.7)	150 (7.2)	225 (4.8)	321 (3.37)	450 (2.41)	750 (1.44)	1124 (0.96)	1499 (0.72)	2249 (0.48)	3212 (0.337)	4497 (0.241)	7496 (0.144)	11244 (0.096)	14992 (0.072)	22487 (0.048)
17	47 (24.7)	79 (14.7)	118 (9.86)	158 (7.36)	236 (4.93)	338 (3.44)	473 (2.46)	788 (1.48)	1182 (0.98)	1576 (0.74)	2364 (0.49)	3377 (0.344)	4728 (0.246)	7880 (0.148)	11819 (0.098)	15759 (0.074)	23639 (0.049)
18	50 (24.9)	83 (15.0)	124 (10.0)	165 (7.54)	248 (5.02)	354 (3.51)	496 (2.51)	826 (1.51)	1239 (1.0)	1652 (0.75)	2478 (0.50)	3540 (0.351)	4956 (0.251)	8260 (0.151)	12390 (0.100)	16520 (0.075)	24780 (0.050)
19	52 (25.5)	86 (15.4)	130 (10.2)	173 (7.76)	259 (5.12)	370 (3.58)	518 (2.56)	864 (1.53)	1296 (1.02)	1728 (0.77)	2591 (0.52)	3702 (0.358)	5183 (0.256)	8638 (0.153)	12957 (0.102)	17276 (0.077)	25914 (0.051)
20	54 (26.1)	90 (15.6)	135 (10.4)	180 (7.82)	271 (5.19)	386 (3.65)	541 (2.60)	902 (1.56)	1353 (1.04)	1803 (0.78)	2705 (0.52)	3864 (0.364)	5410 (0.260)	9017 (0.156)	13526 (0.104)	18034 (0.078)	27051 (0.052)
26	65 (27.0)	109 (16.1)	163 (10.8)	217 (8.08)	326 (5.38)	466 (3.76)	652 (2.69)	1086 (1.61)	1629 (1.08)	2173 (0.807)	3259 (0.538)	4656 (0.376)	6518 (0.269)	10863 (0.161)	16295 (0.108)	21726 (0.081)	32589 (0.054)

NOTES



1. Sample sizes are based upon the Poisson exponential binomial limit.
2. The minimum quality (approximate AQL) required to accept (on the average) 19 of 20 lots is shown in parentheses for information only.



ANNEXE I

LTPD SAMPLING PLAN LOT SIZES LESS THAN, OR EQUAL TO, 200 DEVICES

C=0													
N	10	20	30	40	50	60	80	100	120	150	160	200	
n	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	
2	2.2 65	2.5 66	2.5 67	2.5 67	2.5 67	2.5 68	2.5 68	2.5 68	2.5 68	2.5 68	2.5 68	2.5 68	
4	1.2 36	1.2 40	1.2 42	1.2 42	1.3 42	1.3 43	1.3 43	1.3 43	1.3 43	1.3 43	1.3 44	1.3 44	
5	1.0 29	1.0 33	1.0 34	1.0 35	1.0 35	1.0 35	1.0 36	1.0 36	1.0 37	1.0 37	1.0 37	1.0 37	
8	0.5 15	0.6 20	0.6 22	0.6 23	0.6 23	0.6 23	0.6 24	0.7 24	0.7 24	0.7 24	0.7 24	0.7 25	
10		0.4 15	0.5 17	0.5 19	0.5 19	0.5 19	0.5 20	0.5 20	0.5 20	0.5 20	0.5 20	0.5 20	
16		0.2 6.9	0.25 10	0.25 11	0.3 11	0.3 12	0.3 12	0.3 13	0.3 13	0.3 13	0.3 13	0.3 13	
20			0.2 6.8	0.2 8.0	0.25 8.7	0.25 9.0	0.25 9.4	0.25 10	0.25 10	0.25 10	0.25 10	0.25 11	
25			0.15 4.3	0.15 5.7	0.2 6.4	0.2 6.9	0.2 7.4	0.2 7.5	0.2 7.6	0.2 7.7	0.2 7.8	0.2 7.9	
32				0.1 3.7	0.1 4.4	0.1 5.0	0.1 5.5	0.1 5.9	0.15 6.0	0.15 6.2	0.15 6.3	0.15 6.3	
40					0.1 3.0	0.1 3.4	0.1 4.0	0.1 4.5	0.1 4.6	0.1 4.9	0.1 5.0	0.15 5.0	
50						0.1 2.3	0.1 2.9	0.10 3.3	0.10 3.5	0.10 3.7	0.10 3.7	0.10 3.9	
64							0.08 1.7	0.08 2.2	0.08 2.5	0.08 2.7	0.08 2.8	0.08 2.9	
80								0.07 1.5	0.07 1.7	0.07 2.0	0.07 2.1	0.07 2.2	
100									0.05 1.1	0.05 1.5	0.05 1.5	0.05 1.7	
125										0.04 0.8	0.04 0.9	0.04 1.2	
128												0.04 1.1	
160												0.03 0.7	
C=1													
N	10	20	30	40	50	60	80	100	120	150	160	200	
n	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	
2	27 95	24 95	24 95	23 95	23 95	23 95	23 95	23 95	23 95	22 95	22 95	22 95	
4	15 62	12 66	12 66	11 67	11 67	10 67	10 67	10 67	10 67	9.8 67	9.7 67	9.7 68	
5	13 51	10 55	8.8 56	8.5 57	8.4 57	8.1 58	7.9 58	7.6 58	7.5 58	7.5 58	7.5 58	7.5 58	
8	11 28	7.2 35	6.2 38	5.8 38	5.4 39	5.0 39	4.7 39	4.5 39	4.3 39	4.3 40	4.2 40	4.2 40	
10		6.2 30	5.0 30	4.6 31	4.2 32	4.2 32	4.2 32	3.9 33	3.5 33	3.3 33	3.3 33	3.3 33	
16		5.6 15	4.2 18	3.8 18	3.4 20	3.0 20	2.9 21	2.6 21	2.5 21	2.3 21	2.3 22	2.2 22	
20			4.0 13	3.2 15	2.8 16	2.5 16	2.4 16	2.3 16	2.1 17	2.0 17	2.0 17	2.0 18	
25			3.8 9.2	3.1 11	2.5 12	2.2 13	2.0 13	1.8 13	1.7 13	1.6 14	1.6 14	1.6 14	
32				3.1 7.4	2.4 8.2	2.1 9.0	1.8 9.9	1.6 10	1.5 10.5	1.4 11	1.3 11	1.3 11	
40					2.4 5.9	2.1 6.8	1.6 7.6	1.4 7.8	1.3 8.2	1.2 8.3	1.2 8.4	1.2 8.6	
50						1.7 4.6	1.4 5.6	1.2 6.1	1.2 6.4	1.0 6.5	0.9 6.7	0.9 6.7	
64							1.3 3.8	1.1 4.4	1.0 4.7	0.8 5.0	0.8 5.0	0.7 5.2	
80								1.1 3.0	1.0 3.4	0.8 3.7	0.7 3.8	0.6 4.0	
100									0.9 2.5	0.7 2.8	0.7 2.8	0.6 3.0	
125										0.7 1.9	0.7 2.0	0.5 2.2	
128												0.5 2.2	
160										0.7 1.7	0.7 1.9	0.5 1.5	
C=2													
N	10	20	30	40	50	60	80	100	120	150	160	200	
n	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	AQL LTPD	
4	33 82	28 83	27 84	27 85	27 85	26 85	26 85	26 86	26 86	25 86	25 86	25 86	
5	27 69	23 73	21 74	20 74	20 74	20 75	20 75	19 75	19 75	19 75	19 75	19 75	
8	22 42	15 49	14 49	13 52	13 52	13 52	12 53	12 53	12 53	11 53	11 53	11 53	
10		13 39	11 42	11 42	10 43	10 43	9.6 43	9.2 44	9.1 44	8.9 44	8.9 44	8.7 44	
16		11 22	8.6 25	6.9 27	6.8 27	6.4 27	6.0 28	6.0 29	5.9 29	5.9 29	5.7 29	5.5 30	
20			7.7 19	6.2 21	5.9 22	5.6 22	5.1 23	4.8 23	4.8 23	4.6 23	4.5 24	4.5 24	
25			7.4 13	6.0 16	4.9 17	4.5 17	4.3 18	4.1 18	3.9 18	3.7 18	3.7 19	3.7 19	
32				5.5 11	4.8 12	4.3 13	3.6 14	3.4 14	3.2 14	3.0 14.5	3.0 15	2.9 15	
40					4.6 8.9	3.9 9.8	3.1 11	2.8 12	2.6 12	2.4 12	2.4 12	2.3 12	
50						3.5 6.9	2.8 8.1	2.4 8.4	2.3 8.6	2.1 9.0	2.1 9.3	2.0 9.5	
64							2.6 5.7	2.2 6.2	2.0 6.6	1.8 7.1	1.7 7.1	1.6 7.4	
80								2.1 4.5	1.8 4.9	1.6 5.4	1.5 5.4	1.4 5.6	
100									1.8 3.5	1.4 3.9	1.4 4.0	1.2 4.4	
125										1.4 2.8	1.3 2.9	1.1 3.3	
128												1.1 3.2	
160										1.4 2.6	1.3 2.9	1.1 2.3	

 	ESA/SCC Generic Specification No. 4009		PAGE 37 ISSUE 3
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ANNEXE I

This table gives the AQL and LTPD values associated with certain single sampling plans (Acceptance Number "C", Sample Size "n" and Lot Size "N"). The table has the following features:-

- (a) Calculations are based upon the hyper-geometric distribution (exact theory) for lot sizes of 200 devices or less.
- (b) The AQL of a sampling plan is defined as the interpolated Percent Defective for which there is a 0.95 probability of acceptance under the plan. The AQL so defined need not be a realisable Lot Percent Defective for the lot size involved (e.g., 12 percent is not a realisable Percent Defective for a lot size of 20 devices).
- (c) The LTPD of a sampling plan is defined as the interpolated Percent Defective for which there is a 0.10 probability of lot acceptance under the plan. The LTPD so defined need not be a realisable Lot Percent Defective for the lot size involved.
- (d) The sequence of sample sizes and lot sizes are generated by taking products of preceding numbers in the respective sequences and the numbers 2 and 5.